

FH1302G6
N-Channel Trench Power MOSFET
Description

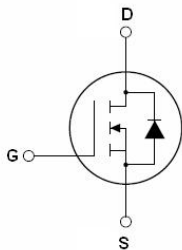
These N-Channel enhancement mode power field effect transistors are using trench DMOS technology. This advanced technology has been especially tailored to minimize on state resistance, provide superior switching performance, and with stand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency fast switching applications.

General Features

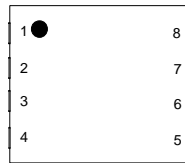
- ◆ $V_{DS} \geq 20V$, $I_D=35A$
 $R_{DS(ON)} = 3.0 \text{ m}\Omega$ (MAX) @ $V_{GS}=4.5V$
 $R_{DS(ON)} = 4.0 \text{ m}\Omega$ (MAX) @ $V_{GS}=2.5V$
- ◆ Advanced trench cell design
- ◆ Low Thermal Resistance

Applications

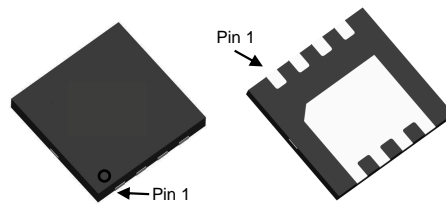
- ◆ Motor Drives
- ◆ DC-DC Converter



Schematic diagram



Marking and pin Assignment



DFN3.3x3.3-8L top and bottom view

Absolute Maximum Ratings ($T_C=25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	Drain-Source Voltage	$T_C = 25^\circ\text{C}$	-	20	V
V_{GS}	Gate-Source Voltage	$T_C = 25^\circ\text{C}$	-	± 12	V
I_D^{****}	Drain Current	$T_C = 25^\circ\text{C}$, $V_{GS} = 10 \text{ V}$	-	35	A
I_{DM}^{*****}	Pulsed Source Current	$T_C = 25^\circ\text{C}$, $V_{GS} = 10 \text{ V}$	-	108	A
P_{tot}^*	Total Power Dissipation	$T_C = 25^\circ\text{C}$	-	41	W
T_{stg}	Storage Temperature		- 55	150	$^\circ\text{C}$
T_J	Junction Temperature		-	150	$^\circ\text{C}$
I_S	Diode Forward Current	$T_C = 25^\circ\text{C}$	-	35	A
$R_{\theta JA}^*$	Thermal Resistance- Junction to Ambient		-	62.5	$^\circ\text{C} / \text{W}$
$R_{\theta JC}^*$	Thermal Resistance- Junction to Case		-	3	

Notes :

- * Surface Mounted on 1 in^2 pad area, $t \leq 10 \text{ sec}$
- ** Pulse width $\leq 10 \mu\text{s}$, duty cycle $\leq 1 \%$
- *** limited by bonding wire

Electrical Characteristics (T_A = 25 °C Unless Otherwise Noted)

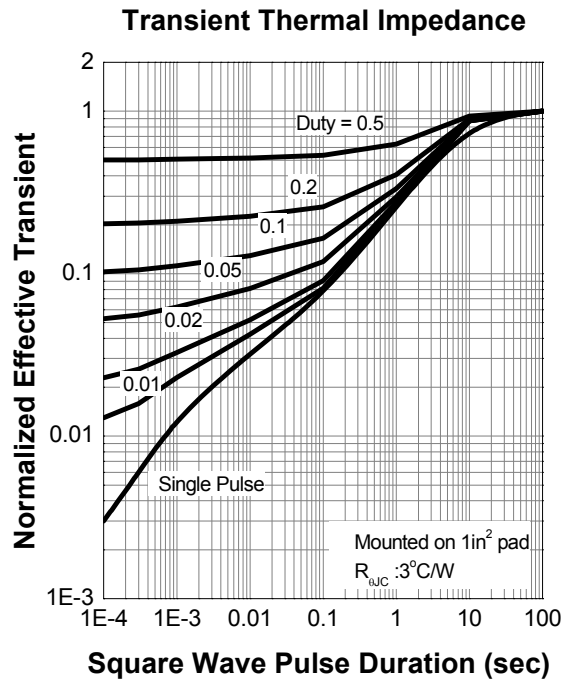
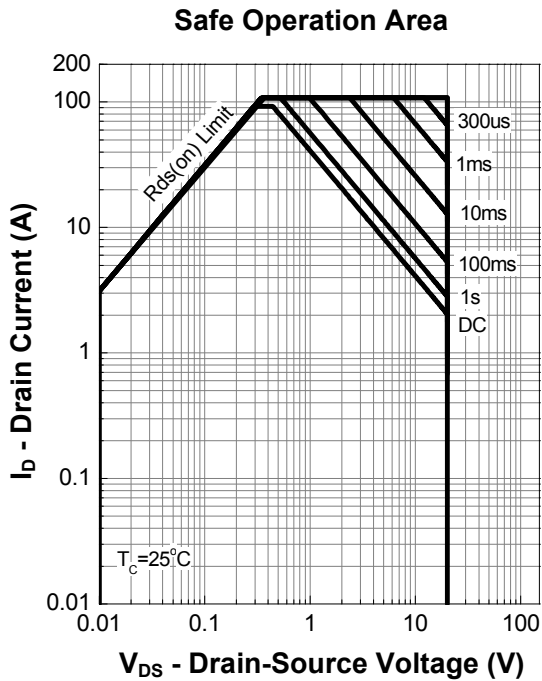
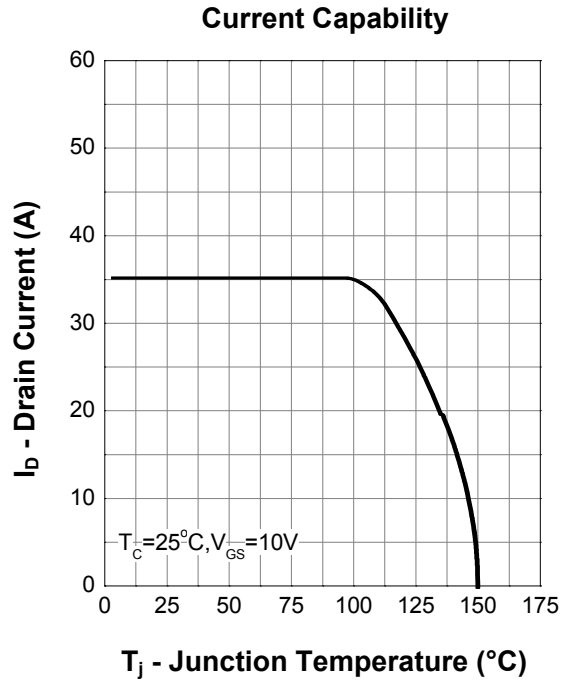
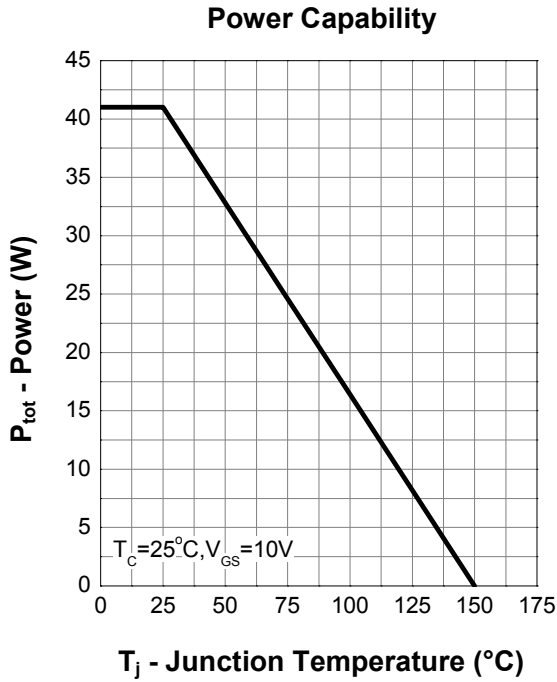
Symbol	Parameter	Conditions	Min	Typ	Max	Unit
Static Characteristics						
B _V DSS	Drain-Source Breakdown Voltage	V _{GS} = 0 V, I _D = 250 μA	20	-	-	V
V _{GS(th)}	Gate Threshold Voltage	V _{DS} = V _{GS} , I _{DS} = 250 μA	0.5	-	1	V
I _{DSS}	Zero Gate Voltage Source Current	V _{DS} = 16 V, V _{GS} = 0 V	-	-	1	μA
		T _J = 85 °C	-	-	30	μA
I _{GSS}	Gate Leakage Current	V _{GS} = ± 12 V, V _{DS} = 0 V	-	-	± 100	nA
R _{DS(ON)} ^a	Drain-Source On-State Resistance	V _{GS} = 4.5 V, I _D = 15 A	-	2.5	3.0	mΩ
		V _{GS} = 2.5 V, I _D = 12 A	-	3.5	4.0	
Diode Characteristics						
V _{SD} ^a	Diode Forward Voltage	I _{SD} = 15 A, V _{GS} = 0 V	-	-	1.1	V
t _{rr}	Reverse Recovery Time	I _{SD} = 15 A, dI _{SD} /dt = 100 A/μs	-	66	-	ns
Q _{rr}	Reverse Recovery Charge		-	89	-	nC
Dynamic Characteristics^b						
C _{iss}	Input Capacitance	V _{GS} = 0 V, V _{DS} = 10 V Frequency = 1 MHz	-	6175	-	pF
C _{oss}	Output Capacitance		-	1693	-	
C _{rss}	Reverse Transfer Capacitance		-	1266	-	
t _{d(on)}	Turn-on Delay Time	V _{DS} = 10 V, V _{GEN} = 10 V, R _G = 4.5 Ω, R _L = 0.6 Ω, I _{DS} = 15 A	-	9.2	-	ns
t _r	Turn-on Rise Time		-	64	-	
t _{d(off)}	Turn-off Delay Time		-	196	-	
t _f	Turn-off Fall Time		-	83	-	
Gate Charge Characteristics^b						
Q _g	Total Gate Charge	V _{DS} = 10 V, V _{GS} = 4.5 V, I _{DS} = 15 A	-	80	-	nC
Q _{gs}	Gate-Source Charge		-	10	-	
Q _{gd}	Gate-Drain Charge		-	24	-	

Notes :

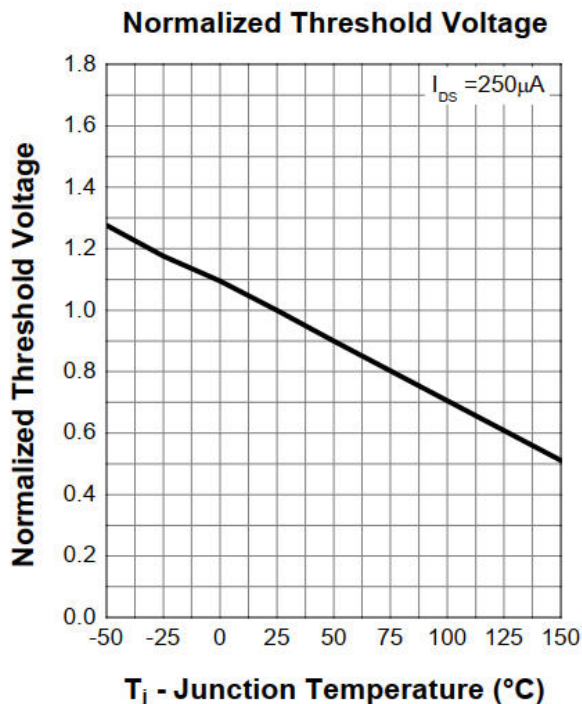
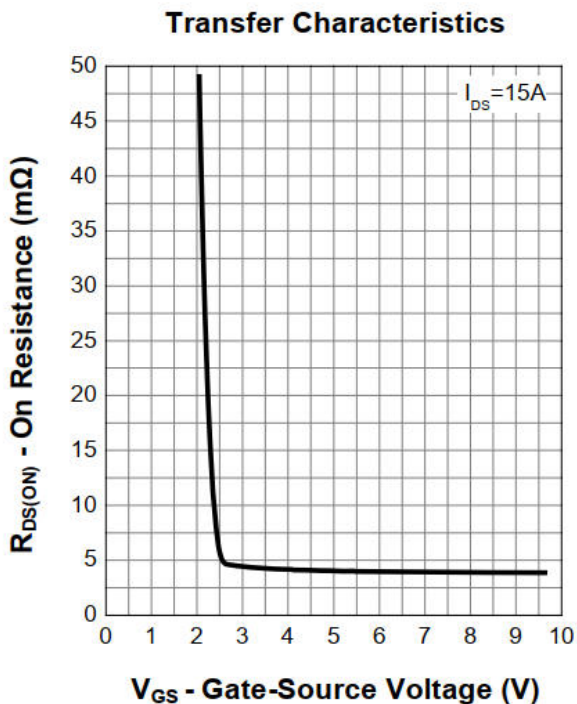
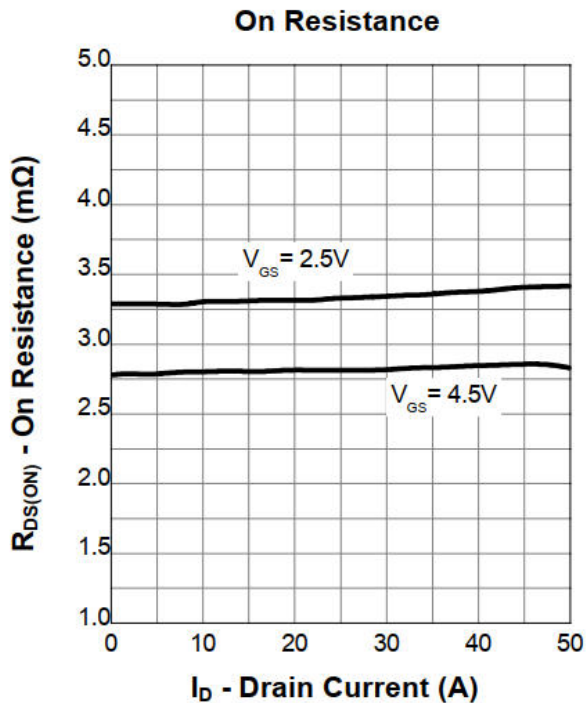
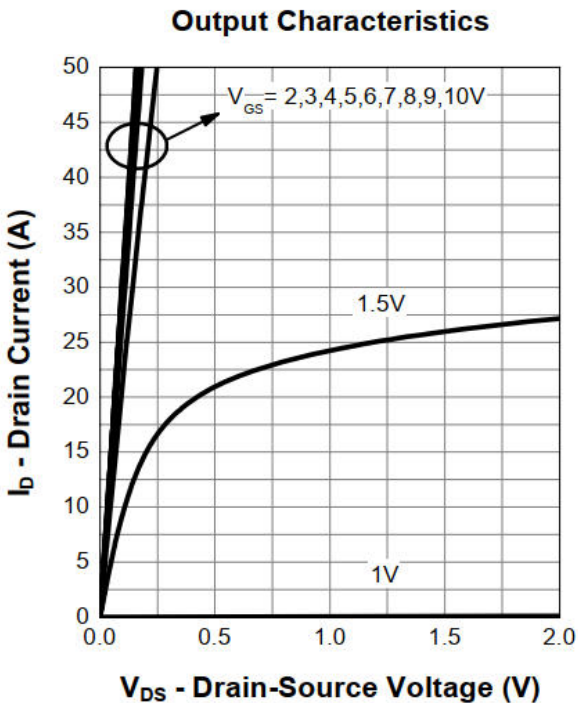
a : Pulse test ; pulse width ≤ 300 μs, duty cycle ≤ 2 %

b : Guaranteed by design, not subject to production testing

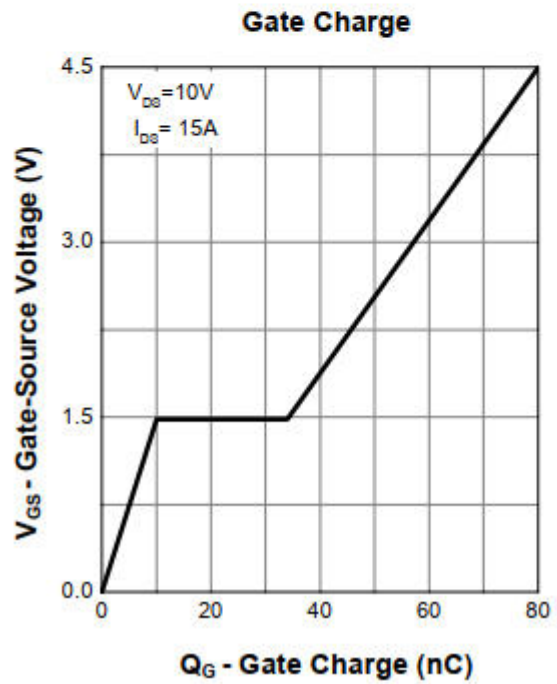
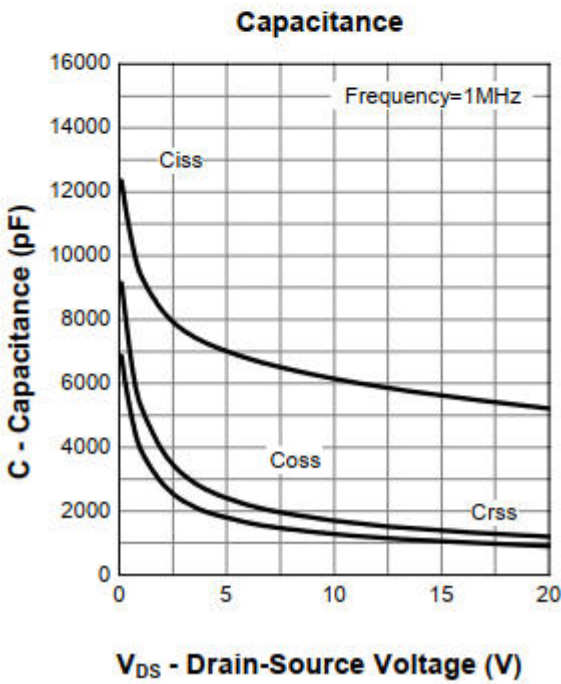
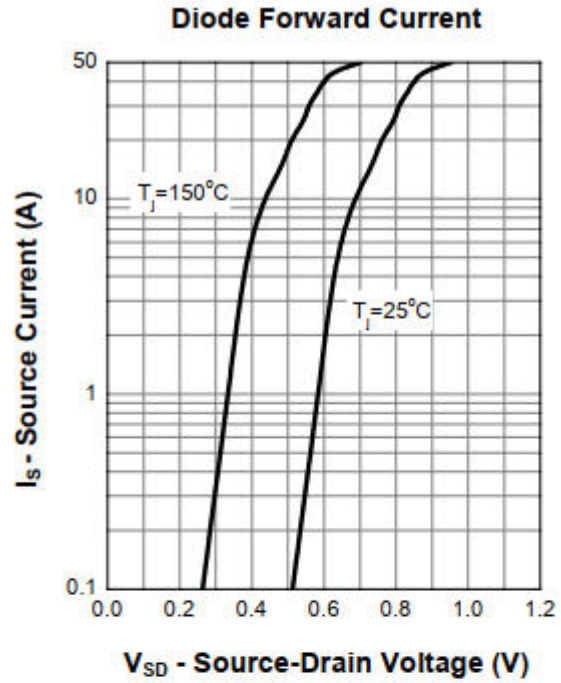
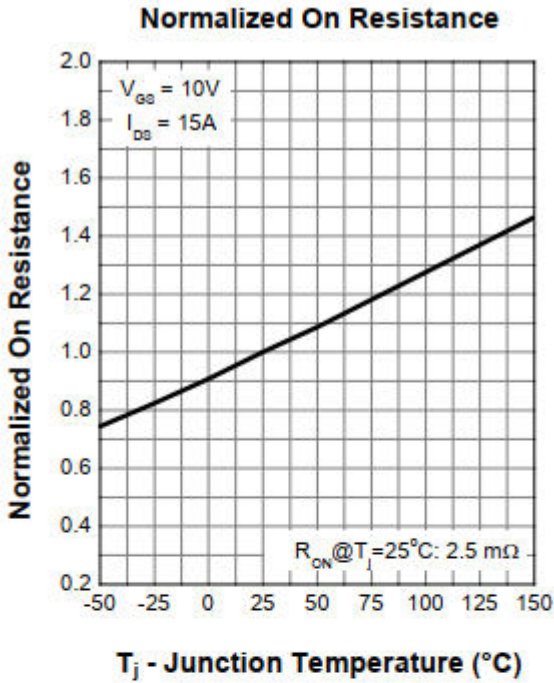
Typical Characteristics (Cont.)



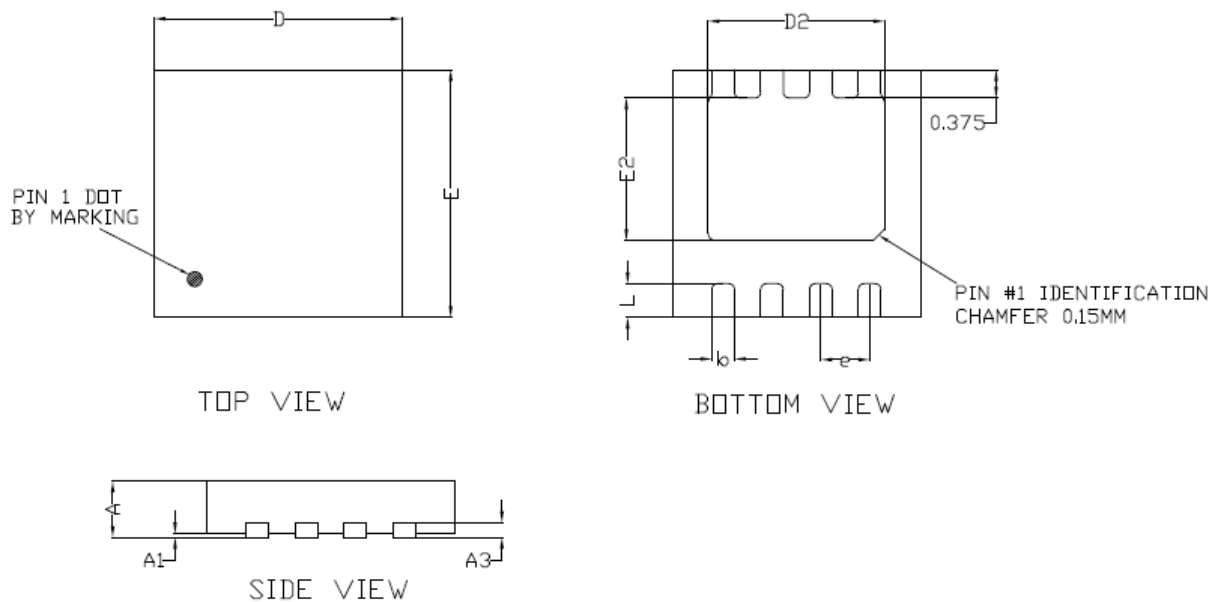
Typical Characteristics (Cont.)



Typical Characteristics (Cont.)



Package Information : DFN3.3*3.3-8L



Lead finish : NiPdAu

Symbol	Dimensions In Millimeters	
	MIN.	MAX.
A	0.7	0.8
A1	0.00	0.05
A3	0.20 REF	
D	3.20	3.40
E	3.20	3.40
D2	2.30	2.40
E2	1.85	1.95
b	0.25	0.35
L	0.35	0.55
e	0.65 BSC	